

# VN35AK, VN66AK, VN67AK, VN98AK, VN99AK

## n-Channel Enhancement-mode Vertical Power MOSFET

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**FEATURES**

- High speed, high current switching
- High gain-bandwidth product
- Inherently temperature stable
- Extended safe operating area
- Simple DC biasing
- Requires almost zero current drive

**APPLICATIONS**

- High current analog switches
- RF power amplifiers
- Laser diode pulsers
- Line drivers
- Logic buffers
- Pulse amplifiers

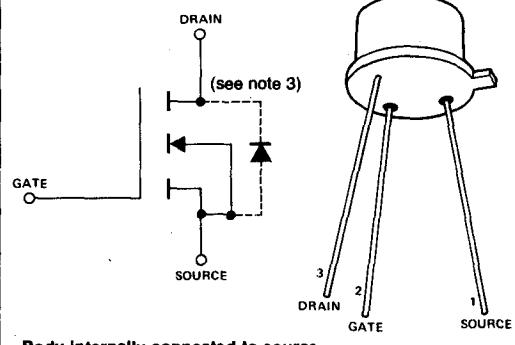
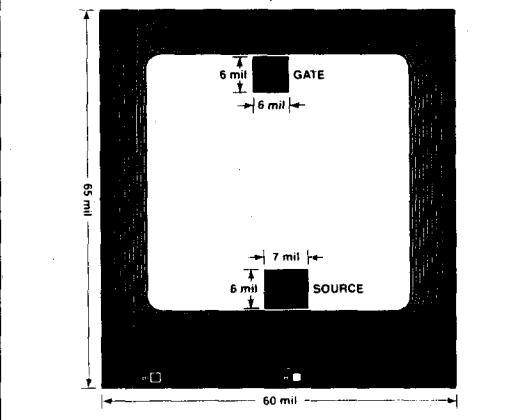
**ABSOLUTE MAXIMUM RATINGS**  
( $T_A = 25^\circ\text{C}$  unless otherwise noted)

Drain-source Voltage	
VN35AK .....	35V
VN66AK, VN67AK .....	60V
VN98AK, VN99AK .....	90V
Drain-gate Voltage	
VN35AK .....	35V
VN66AK, VN67AK .....	60V
VN98AK, VN99AK .....	90V
Continuous Drain Current (see note 1)	1.2A
Peak Drain Current (see note 2)	3.0A
Gate-source Forward Voltage	+30V
Gate-source Reverse Voltage	-30V
Thermal Resistance, Junction to Case	$20^\circ\text{C}/\text{W}$
Continuous Device Dissipation at (or below)	
$25^\circ\text{C}$ Case Temperature .....	6.25W
Linear Derating Factor .....	50mW/ $^\circ\text{C}$
Operating Junction	
Temperature Range .....	-55 to $+150^\circ\text{C}$
Storage Temperature Range .....	-55 to $+150^\circ\text{C}$
Lead Temperature	
(1/16 in. from case for 10 sec) .....	+300°C

**Note 1.**  $T_C = 25^\circ\text{C}$ ; controlled by typical  $r_{DS(on)}$  and maximum power dissipation.

**Note 2.** Pulse width 80 $\mu\text{sec}$ , duty cycle 1.0%.

**Note 3.** The Drain-source diode is an integral part of the MOSFET structure.

**SCHEMATIC DIAGRAM** (OUTLINE DWG. TO-39)

**CHIP TOPOGRAPHY**


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INTERSIL

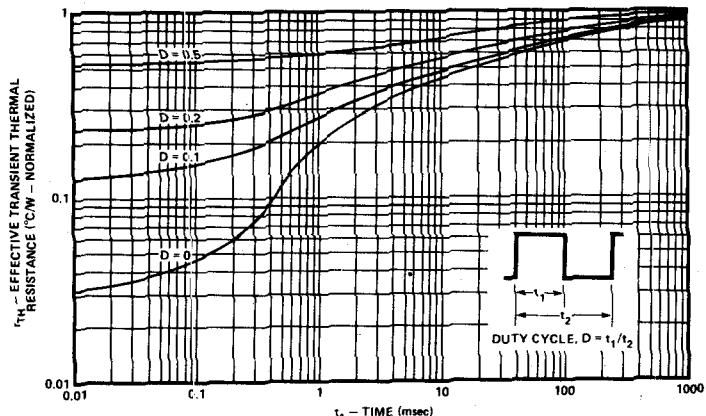
## ELECTRICAL CHARACTERISTICS (25°C unless otherwise noted)

CHARACTERISTIC			VN35AK			VN66AK VN67AK			VN98AK VN99AK			UNIT	TEST CONDITIONS		
			MIN	TYP	MAX	MIN	TYP	MAX	MIN	TYP	MAX				
1	BV <sub>DSS</sub>	Drain-Source Breakdown	35		60			90				V	V <sub>GS</sub> = 0, I <sub>D</sub> = 10μA		
2	V <sub>G(th)</sub>	Gate-Threshold Voltage	0.8		2.0	0.8		2.0	0.8		2.0	V	V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> = 1mA		
3	I <sub>GSS</sub>	Gate-Body Leakage		0.5	100		0.5	100		0.5	100	nA	V <sub>GS</sub> = 15V, V <sub>DS</sub> = 0		
4					500			500			500		V <sub>GS</sub> = 15V, V <sub>DS</sub> = 0, TA = 125°C (Note 2)		
5					10			10			10		I <sub>DSS</sub> = Max. Rating, V <sub>GS</sub> = 0		
6	I <sub>DSS</sub>	Zero Gate Voltage Drain Current			500			500			500	μA	V <sub>DS</sub> = 0.8 Max. Rating, V <sub>GS</sub> = 0, TA = 125°C (Note 2)		
7	I <sub>D(on)</sub>	ON-State Drain Current	1.0	2.0		1.0	2.0		1.0	2.0		nA	V <sub>DS</sub> = 25V, V <sub>GS</sub> = 0		
8	V <sub>D(on)</sub>	Drain-Source Saturation Voltage	VN66AK				1.0			1.1		A	V <sub>DS</sub> = 25V, V <sub>GS</sub> = 10V		
9		VN98AK					2.2	3.0	2.2	4.0		V	V <sub>GS</sub> = 5V, I <sub>D</sub> = 0.3A		
10		VN35AK		1.0			1.1			1.2			V <sub>GS</sub> = 10V, I <sub>D</sub> = 1.0A		
11		VN67AK					2.2	3.5	2.2	4.5			V <sub>GS</sub> = 5V, I <sub>D</sub> = 0.3A		
12		VN99AK		2.2	2.5								V <sub>GS</sub> = 10V, I <sub>D</sub> = 1.0A		
13	g <sub>fs</sub>	Forward Transconductance	170	250		170	250		170	250		mΩ	V <sub>DS</sub> = 24V, I <sub>D</sub> = 0.5A, f = 1KHz		
14	C <sub>iss</sub>	Input Capacitance		40	50		40	50		40	50				
15	C <sub>oss</sub>	Common Source Output Capacitance		38	45		35	40		32	40	pF	V <sub>GS</sub> = 0, V <sub>DS</sub> = 24V, f = 1MHz	(Note 1)	
16	C <sub>rss</sub>	Reverse Transfer Capacitance		7	10		6	10		5	10				
17	t <sub>on</sub>	Turn ON Time		3	8		3	8		3	8	ns			
18	t <sub>off</sub>	Turn OFF Time		3	8		3	8		3	8				

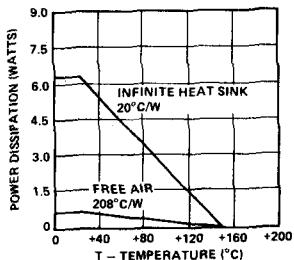
Note 1. Pulse test — 80μs pulse, 1% duty cycle.

Note 2. Sample test.

## THERMAL RESPONSE

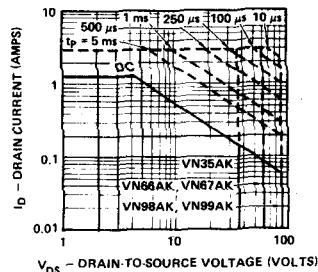


POWER DISSIPATION vs CASE OR AMBIENT TEMPERATURE



DC SAFE OPERATING REGION

T<sub>c</sub> = 25°C



BREAKDOWN VOLTAGE VARIATION WITH TEMPERATURE

